## **STL10N60M2**



## N-channel 600 V, 0.580 Ω typ., 5.5 A MDmesh II Plus™ low Qg Power MOSFET in a PowerFLAT™ 5x6 HV package

Datasheet - production data

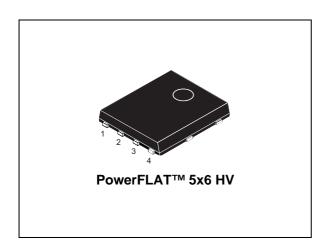
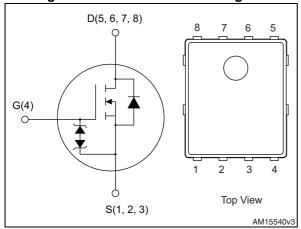


Figure 1. Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STL10N60M2	650 V	0.660 Ω	5.5 A

- Extremely low gate charge
- Lower R<sub>DS(on)</sub> x area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

#### **Applications**

· Switching applications

#### **Description**

This device is an N-channel Power MOSFET developed using a new generation of MDmesh™ technology: MDmesh II Plus™ low Qg. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

Order code	Marking	Package	Packaging
STL10N60M2	10N60M2	PowerFLAT™ 5x6 HV	Tape and reel

Contents STL10N60M2

## **Contents**

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves)	6
3	Test circuits	8
4	Package mechanical data	9
5	Packaging mechanical data	3
6	Revision history 1	15

STL10N60M2 Electrical ratings

# 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	± 25	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	5.5	А
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 100 °C	3.5	А
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	22	А
P <sub>TOT</sub> <sup>(2)</sup>	Total dissipation at T <sub>C</sub> = 25 °C	48	W
I <sub>AR</sub>	Avalanche current, repetitive or not- repetitive (pulse width limited by T <sub>j</sub> max)	1.5	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	110	mJ
dv/dt (3)	Peak diode recovery voltage slope	15	V/ns
dv/dt (4)	MOSFET dv/dt ruggedness	50	V/ns
T <sub>stg</sub>	Storage temperature	- 55 to 150	°C
T <sub>j</sub>	Max. operating junction temperature	150	°C

<sup>1.</sup> The value is limited by package

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	2.6	°C/W
R <sub>thj-amb</sub> <sup>(1)</sup>	Thermal resistance junction-amb max	59	°C/W

<sup>1.</sup> When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu

<sup>2.</sup> Pulse width limited by safe operating area

<sup>3.</sup>  $I_{SD} \le 5.5 \text{ A, di/dt} \le 400 \text{ A/µs, } V_{DSpeak} \le V_{(BR)DSS}, V_{DD} = 80\% V_{(BR)DSS}$ 

<sup>4.</sup>  $V_{DS} \le 480 \text{ V}$ 

Electrical characteristics STL10N60M2

## 2 Electrical characteristics

(T<sub>C</sub> = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0	600			V
1	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 600 V			1	μΑ
DSS		V <sub>DS</sub> = 600 V, T <sub>C</sub> = 125 °C			100	μΑ
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 25 V			100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$		0.580	0.660	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	400	-	pF
C <sub>oss</sub>	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz,	-	22	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	$V_{GS} = 0$	-	0.84	-	pF
C <sub>oss eq.</sub> <sup>(1)</sup>	Output equivalent capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$	-	83	-	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz open drain	-	6.4	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 7.5 A,	-	13.5	-	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V (see <i>Figure 15</i> )	-	2.1	-	nC
$Q_{gd}$	Gate-drain charge		-	7.2	-	nC

<sup>1.</sup>  $C_{\rm oss~eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{\rm oss}$  when  $V_{\rm DS}$  increases from 0 to 80%  $V_{\rm DS}$ .

Table 6. Switching times

<b>3</b>						
Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t <sub>d(on)</sub>	Turn-on delay time		-	8.8	-	ns
t <sub>r</sub>	Rise time	$V_{DD} = 300 \text{ V}, I_{D} = 3.75 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 19</i> )	-	8	-	ns
t <sub>d(off)</sub>	Turn-on delay time		-	32.5	-	ns
t <sub>f</sub>	Fall time		-	13.2	-	ns



4/16 DocID025439 Rev 2

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$I_{SD}$	Source-drain current		-		5.5	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		22	Α
V <sub>SD</sub> (2)	Forward on voltage	$I_{SD} = 7.5 \text{ A}, V_{GS} = 0$	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 7.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	-	270		ns
Q <sub>rr</sub>	Reverse recovery charge	V <sub>DD</sub> = 60 V (see <i>Figure 16</i> )	-	2		μC
I <sub>RRM</sub>	Reverse recovery current		-	14.4		Α
t <sub>rr</sub>	Reverse recovery time	V <sub>DD</sub> = 60 V	-	376		ns
Q <sub>rr</sub>	Reverse recovery charge	$di/dt = 100 \text{ A/}\mu\text{s}, I_{SD} = 7.5 \text{ A}$	-	2.8		μC
I <sub>RRM</sub>	Reverse recovery current	T <sub>j</sub> =150 °C (see <i>Figure 16</i> )	-	15		Α

<sup>1.</sup> Pulse width limited by safe operating area.

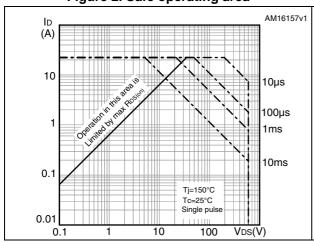
<sup>2.</sup> Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

Electrical characteristics STL10N60M2

### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance



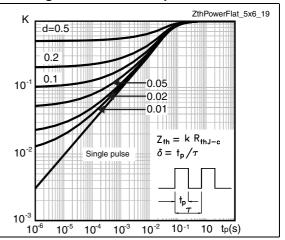
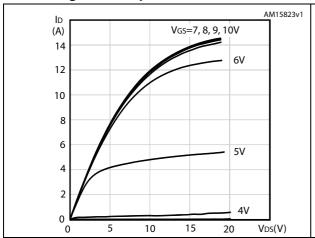


Figure 4. Output characteristics

Figure 5. Transfer characteristics



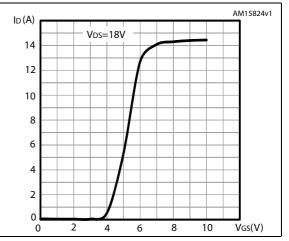
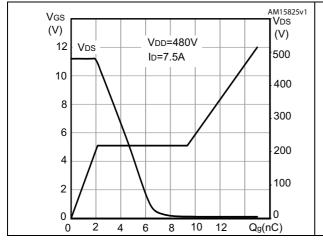
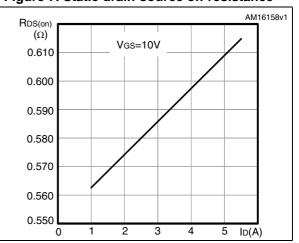


Figure 6. Gate charge vs gate-source voltage

Figure 7. Static drain-source on-resistance

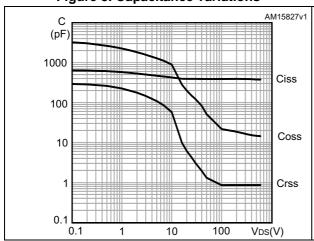




577

Figure 8. Capacitance variations

Figure 9. Output capacitance stored energy



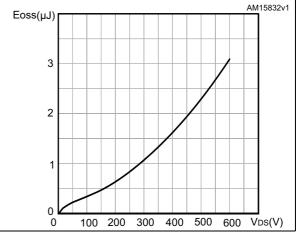
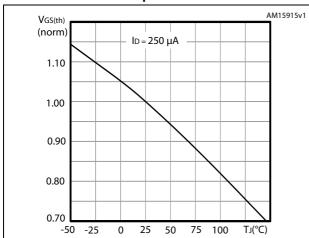


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on-resistance vs temperature



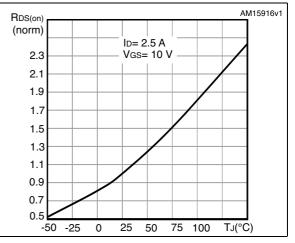
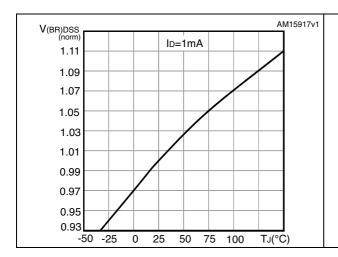
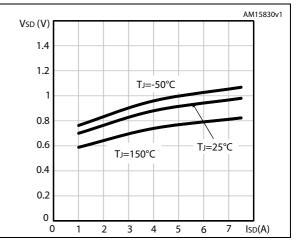


Figure 12. Normalized  $V_{(BR)DSS}$  vs temperature

Figure 13. Source-drain diode forward characteristics





Test circuits STL10N60M2

## 3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

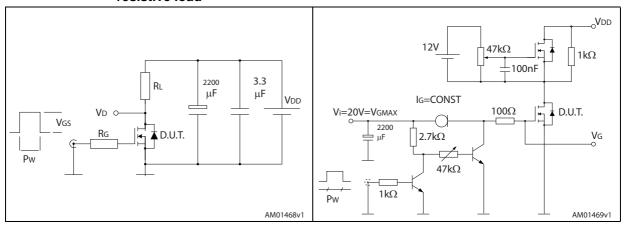


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

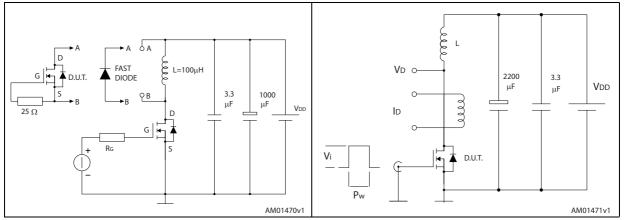
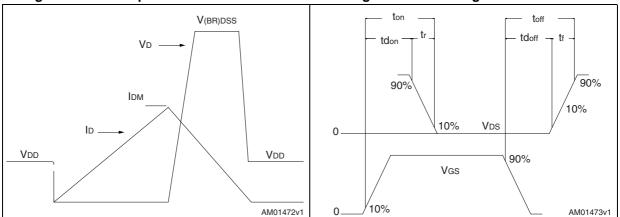


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



57

# 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.



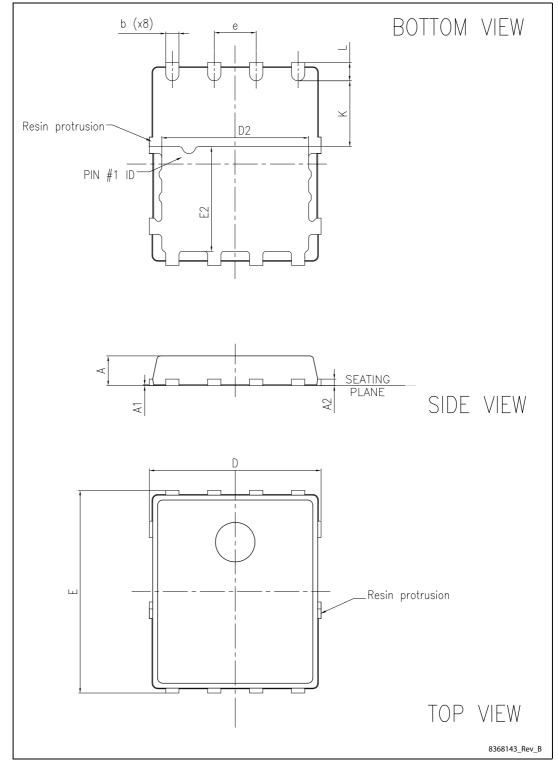


Figure 20. PowerFLAT™ 5x6 HV drawing



Table 8. PowerFLAT™ 5x6 HV mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
А	0.80		1.00
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
D	5.00	5.20	5.40
Е	5.95	6.15	6.35
D2	4.30	4.40	4.50
E2	3.10	3.20	3.30
е		1.27	
L	0.50	0.55	0.60
K	1.90	2.00	2.10



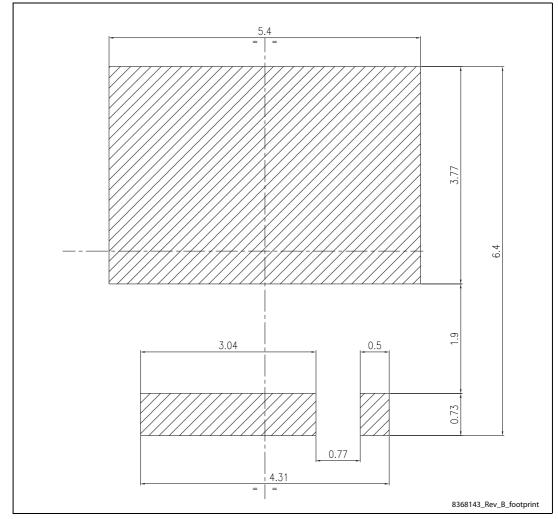


Figure 21. PowerFLAT™ 5x6 HV recommended footprint (dimensions are in mm)

## 5 Packaging mechanical data

(I) Measured from centerline of sprocket hole to centerline of pocket.

 $\label{eq:continuous} \begin{tabular}{ll} (II) & Cumulative tolerance of 10 sprocket holes is <math display="inline">\pm~0.20~. \end{tabular}$  (III) Measured from centerline of sprocket hole to centerline of pocket.

Do (0.30±0.05)

Do (0.1.55±0.05)

Do (0.55±0.05)

Do (0.55±0.05)

Do (0.50±0.1)

Do (0.50±0.1)

Do (0.50±0.1)

Do (0.50±0.1)

Ao(6.30±0.1)

Fig. (0.30±0.1)

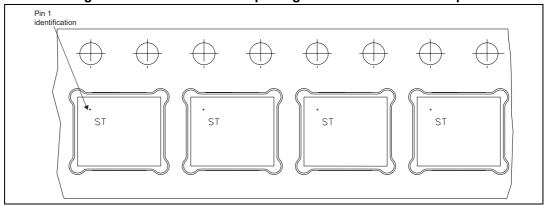
Ao(6.30±0.1)

SECTIONYY

Figure 22. PowerFLAT™ 5x6 tape<sup>(a)</sup>

Figure 23. PowerFLAT™ 5x6 package orientation in carrier tape.

Base and bulk quantity 3000 pcs



a. All dimensions are in millimeters.



8234350\_Tape\_rev\_C

All dimensions are in millimeters

8234350\_Reel\_rev\_C

Figure 24. PowerFLAT™ 5x6 reel

577

STL10N60M2 Revision history

# 6 Revision history

Table 9. Document revision history

Date	Revision	Changes
28-Oct-2013	1	First release.
26-Mar-2014	2	Document status promoted from preliminary to production data.  Minor text changes.

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DocID025439 Rev 2 16/16

